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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/622,982	CHAN ET AL.	
Examiner	Art Unit	
Liang-che Alex Wang	2155	

SEARCHED			
Class	Subclass	Date	Examiner
709	205-207	10/18/2006	LW
715	752	10/18/2006	LW
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH	'ES Strategy)
	DATE	EXMR
EAST Text Search: USPAT, USPUB, EPO, JPO, DERWENT	10/18/2006	LW
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